

<b>Notice of References Cited</b>	Application/Control No. 10/569,495		Applicant(s)/Patent Under Reexamination HINO ET AL.	
	Examiner Charles I. Boyer		Art Unit 1796	Page 1 of 1

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*	B	US-2006/0234893	10-2006	Busch et al.	510/376
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